

Comparative study of isothermal grain growth of CdS and CdTe in the presence of halide fluxes

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High temperature electrical conductivity in ZnS:Cu:Cl ceramics and in Cd_{Sex}Te_{1-x} polycrystalline solid solutions

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Hydrogen interaction with point defects in the Si-SiO₂ structures and its influence on the interface properties

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Interaction of point defects with impurities in the Si-SiO₂ system and its influence on the interface properties

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